

PDI Topical Workshop on in situ and in vivo real-time x-ray scattering applying high-brilliance synchrotron radiation



Monday, Feb. 22, 2010

09:30–10:15 Registration with Coffee

10:15–10:30 Opening:

Henning Riechert, Wolfgang Braun

10:30–11:00 T. W. Cornelius (ESRF, Grenoble)

Mechanical properties of individual nanostructures studied by in-situ AFM and mXRD

11:00–11:30 R. Felici (ESRF, Grenoble)

In-situ structural and morphological characterization of surfaces during processes

11:30–12:00 O. Balmes (ESRF, Grenoble)

In-situ x-ray diffraction studies of catalytic surfaces

12:00–13:30 Lunch break

13:30–14:00 V. M. Kaganer (Paul-Drude-Institut, Berlin)

Kinetic optimum of Volmer-Weber growth

14:00–14:30 P. Fenter (Argonne National Laboratory)

Imaging Structures and Processes at Solid-Aqueous Interfaces*

14:30–15:00 F. U. Renner (Max-Planck-Institut für Eisenforschung)

Alloying and Dealloying: Electrochemical Model Interfaces

15:00–15:30 Coffee break

15:30–16:00 A. R. Woll (Cornell University)

Using time resolved x-ray reflectivity to study interactions at the organic thin film/substrate interface: recent observations and progress in quantitative analysis

16:00–16:30 J. D. Ferguson (Cornell University)

Direct Measurements of Surface Diffusion and Surface Morphology During Pulsed Laser Deposition of Ternary Oxide Heterointerfaces

16:30–17:00 Coffee break

17:00–17:30 T. Hosokai (Universität Tübingen)

Simultaneous Real-Time Optical and XRay Experiments of Organic Thin Films during Growth

17:30–18:00 A. Hinderhofer (Universität Tübingen)

Smoothing and coherent structure formation in organic-organic heterostructure growth

18:00–19:00 Sightseeing stroll to the conference dinner location

19:00 Conference dinner

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Tuesday, Feb. 23, 2010

08:30–09:00 B. Krause (Karlsruher Institut für Technologie)

The ANKA UHV lab

09:00–09:30 S. Kowarik (Humboldt-Universität zu Berlin)

Optimising real-time X-ray measurements by accessing a range of reciprocal space

09:30–10:00 A. Mikkelsen (Lund University)

Future in-situ studies of semiconductor and oxide nanostructures at Lund University

10:00–10:30 Coffee break

10:30–11:00 O. M. Magnussen (Christian-Albrechts-Universität zu Kiel)

Surface x-ray scattering studies of solid-liquid and liquid-liquid interfaces

11:00–11:30 S. Milita (CNR-IMM)

Monitoring the organic molecules organization on nano-confined systems

11:30–12:00 T. Schülli (INAC/SP2M (NRS))

In situ nucleation of nanowires: catalysts and early growth stages of Si nanowires

12:00–13:30 Lunch break

13:30–14:00 M. Takahasi (Synchrotron Radiation Research Center)

In situ X-ray diffraction study on molecular-beam epitaxy of high-density InAs/GaAs(001) quantum dots

14:00–14:30 A. Davydok (Universität Siegen)

X-ray investigations of strain accommodation in GaAs nanorods/Si[111]-substrate system

14:30–14:45 Concluding remarks: Michael Hanke, Frank Schreiber

14:45–18:00 Visit of PDI's PHARAO beamline at BESSY